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ELEKTRIVARUSTUSSÜSTEEMIDES. OSA 2:
FUNKTSIONAALKATSETUSED JA
MÕÕTEMÄÄRAMATUSNÕUDED**

**Power quality measurement in power supply systems -
Part 2: Functional tests and uncertainty requirements**

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN 62586-2:2014 sisaldab Euroopa standardi EN 62586-2:2014 ingliskeelset teksti.	This Estonian standard EVS-EN 62586-2:2014 consists of the English text of the European standard EN 62586-2:2014.
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English Version

**Power quality measurement in power supply systems - Part 2:
Functional tests and uncertainty requirements
(IEC 62586-2:2013)**

Mesure de la qualité de l'alimentation dans les réseaux
d'alimentation - Partie 2: Essais fonctionnels et exigences
d'incertitude
(CEI 62586-2:2013)

Messung der Spannungsqualität in
Energieversorgungssystemen - Teil 2: Funktionsprüfungen
und Anforderungen an die Messunsicherheit
(IEC 62586-2:2013)

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This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

Foreword

The text of document 85/461/FDIS, future edition 1 of IEC 62586-2, prepared by IEC/TC 85 "Measuring equipment for electrical and electromagnetic quantities" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62586-2:2014.

The following dates are fixed:

- latest date by which the document has to be (dop) 2014-12-20
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2017-01-16
standards conflicting with the
document have to be withdrawn

This document has been prepared under a mandate given to CENELEC by the European Commission and the European Free Trade Association, and supports essential requirements of EU Directive.

For the relationship with EU Directive see informative Annex ZZ, which is an integral part of this document.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 62586-2:2013 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60359	NOTE	Harmonized as EN 60359.
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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61000-2-4	-	Electromagnetic compatibility (EMC) - Part 2-4: Environment - Compatibility levels in industrial plants for low-frequency conducted disturbances	EN 61000-2-4	-
IEC 61000-4-7	-	Electromagnetic compatibility (EMC) - Part 4-7: Testing and measurement techniques - General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto	EN 61000-4-7	-
IEC 61000-4-15	-	Electromagnetic compatibility (EMC) - Part 4-15: Testing and measurement techniques - Flickermeter - Functional and design specifications	EN 61000-4-15	-
IEC 61000-4-30	2008	Electromagnetic compatibility (EMC) - Part 4-30 : Testing and measurement techniques - Power quality measurement methods	EN 61000-4-30	2009
IEC 62586-1	-	Power quality measurement in power supply systems - Part 1: Power Quality Instruments (PQI)	EN 62586-1	-

Annex ZZ (informative)

Coverage of Essential Requirements of EU Directives

This European Standard has been prepared under a mandate given to CENELEC by the European Commission and the European Free Trade Association and within its scope the standard covers protection requirements of Annex I Article 1 of the EU Directive 2004/108/EC.

Compliance with this standard provides one means of conformity with the specified essential requirements of the Directive concerned.

WARNING: Other requirements and other EU Directives may be applicable to the products falling within the scope of this standard.

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